Sheet 1 of 1			4						
FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT(S)				ATTY DOCKET NO. 2004_0409		SERIAL N	10/798396		
				APPLICANT Setsuo KAJIWARA et al.					
(Use several sheets if necessary)  Date Submitted to PTO: March 12, 2004				FILING DATE March 12, 2004			GROUP 1742		
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GW	AA	6,001,195	12/1999	Kajiwara et al.					
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	AJ								
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GW	AL	Merriman, A.D., "A Dictionary of Metallurgy", MacDonald & Evans, Ltd, London, page 138, 1958							
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GW	AO	Kajiwara et al., "Formation of nanocrystals with an identical orientation in sputter-deposited Ti-Ni thin films", Philosophical Magazine Letters, Vol. 74, No. 6, 395-404, December 1996							
EXAMINER /	DATE CONSIDER	DATE CONSIDERED 09/01/2006							

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of form with next communication to applicant.